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FQA7N90_F109 900V N-Channel MOSFET

Features

- 7.4A, 900V, $R_{DS(on)}$ = 1.55 Ω @V_{GS} = 10 V Low gate charge (typical 45 nC)
- Low Crss (typical 20pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- RoHS compliant

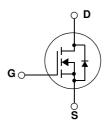


Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies, active power factor correction, electronic lamp ballast based on half bridge topology.





Absolute Maximum Ratings

Symbol	Parameter		FQA7N90_F109	Units	
V _{DSS}	Drain-Source Voltage		900	V	
I _D	Drain Current - Continuous (T _C = 25°C)		7.4	Α	
	- Continuous (T _C = 100°C)		4.7	Α	
I _{DM}	Drain Current - Pulsed	(Note 1)	29.6	Α	
V _{GSS}	Gate-Source Voltage		± 30	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	830	mJ	
I _{AR}	Avalanche Current	(Note 1)	7.4	Α	
E _{AR}	Repetitive Avalanche Energy (Note 1)		22	mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.0	V/ns	
P _D	Power Dissipation (T _C = 25°C)		220	W	
	- Derate above 25°C		1.75	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.57	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.24		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQA7N90	FQA7N90_F109	TO-3PN	-	-	30

Electrical Characteristics T_C = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Charac	teristics				ı	
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	900			V
$\Delta BV_{DSS}/$ ΔT_J	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, Referenced to 25°C		1.0		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 900 V, V _{GS} = 0 V			10	μА
		V _{DS} = 720 V, T _C = 125°C			100	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
On Charact	eristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 3.7 A		1.2	1.55	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 50 V, I _D = 3.7 A (Note 4)		8.0		S
Dynamic Ch	naracteristics					
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,		1750	2280	pF
C _{oss}	Output Capacitance	f = 1.0 MHz		170	220	pF
C _{rss}	Reverse Transfer Capacitance			20	26	pF
Switching C	Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = 450 V, I _D = 7.4A,		40	90	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		100	210	ns
t _{d(off)}	Turn-Off Delay Time	ALL 4.5		100	210	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		70	150	ns
Qg	Total Gate Charge	V _{DS} = 720 V, I _D = 7.4A,		45	59	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		10		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		21		nC
Drain-Source	ce Diode Characteristics and Maximum Ratings	3			1	11.
I _S	Maximum Continuous Drain-Source Diode Fo	rward Current			7.4	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forwar	d Current			29.6	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 7.4 A			1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 7.4 A,		650		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		6.1		μС

NOTES:

- 1. Repetitive Rating : Pulse width limited by maximum junction temperature
- 2. L = 28.6mH, I $_{AS}$ =7.4A, V $_{DD}$ = 50V, R $_{G}$ = 25 Ω , Starting T $_{J}$ = 25°C
- 3. $I_{SD} \le 7.4 A$, di/dt $\le 200 A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting T_J = $25^{\circ}C$
- 4. Pulse Test : Pulse width $\leq 300 \mu s,$ Duty cycle $\leq 2\%$
- 5. Essentially independent of operating temperature

Typical Performance Characteristics

Figure 1. On-Region Characteristics

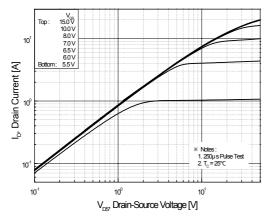


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

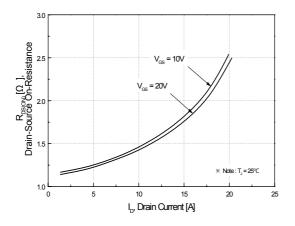


Figure 5. Capacitance Characteristics

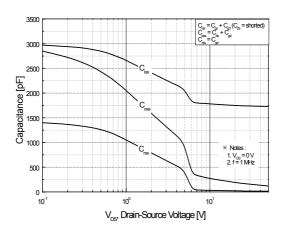


Figure 2. Transfer Characteristics

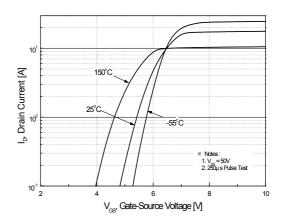


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

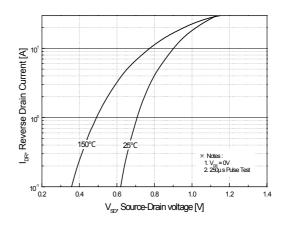
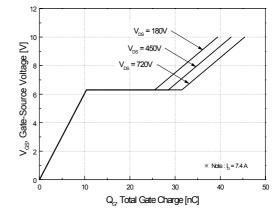


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

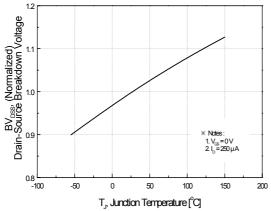


Figure 9. Maximum Safe Operating Area

Figure 8. On-Resistance Variation vs. Temperature

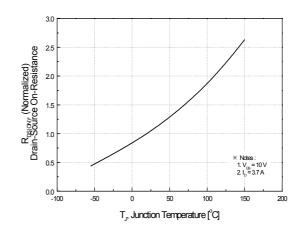


Figure 10. Maximum Drain Current vs. Case Temperature

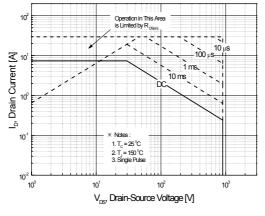
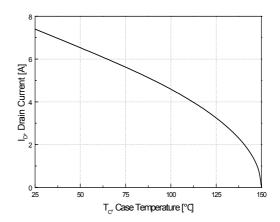
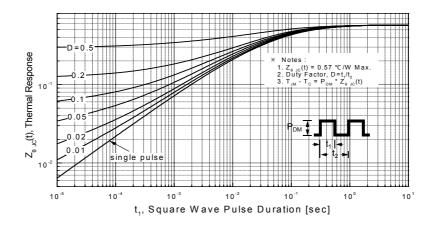
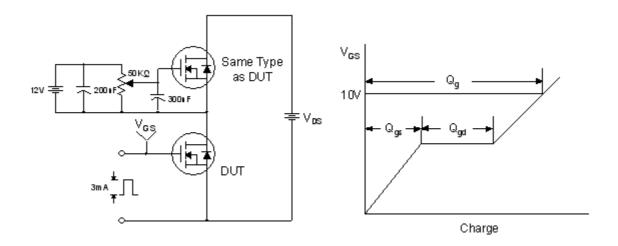


Figure 11. Transient Thermal Response Curve

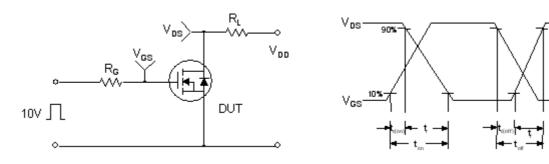




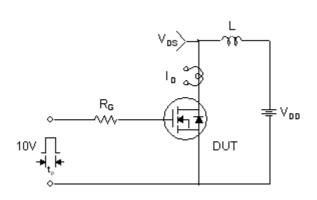
Gate Charge Test Circuit & Waveform

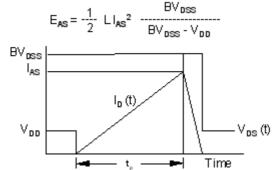


Resistive Switching Test Circuit & Waveforms

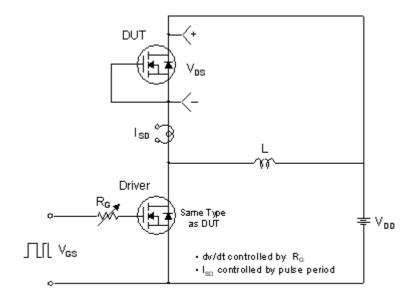


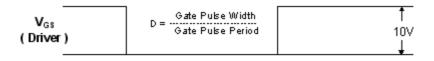
Unclamped Inductive Switching Test Circuit & Waveforms

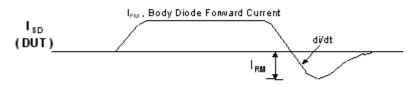


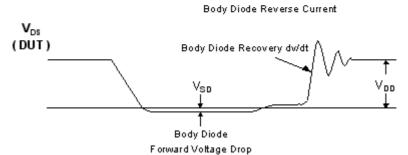


Peak Diode Recovery dv/dt Test Circuit & Waveforms



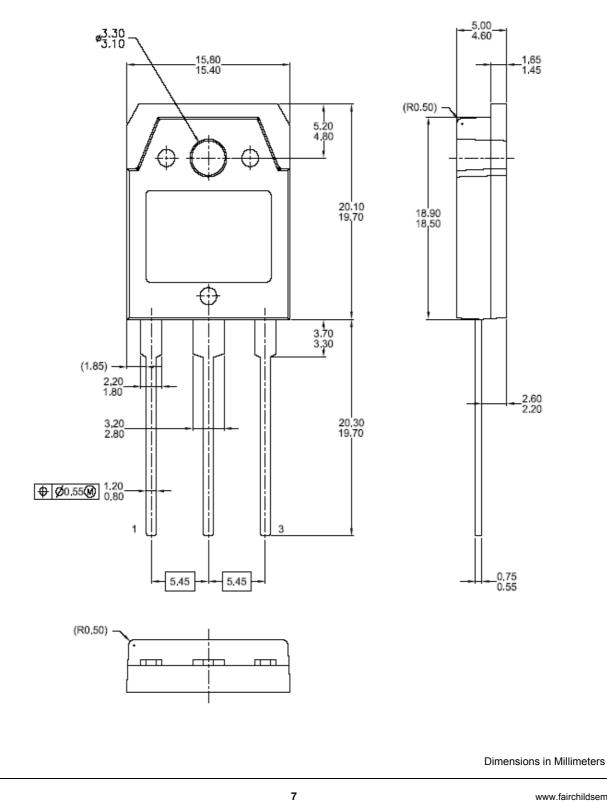






Mechanical Dimensions

TO-3PN







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